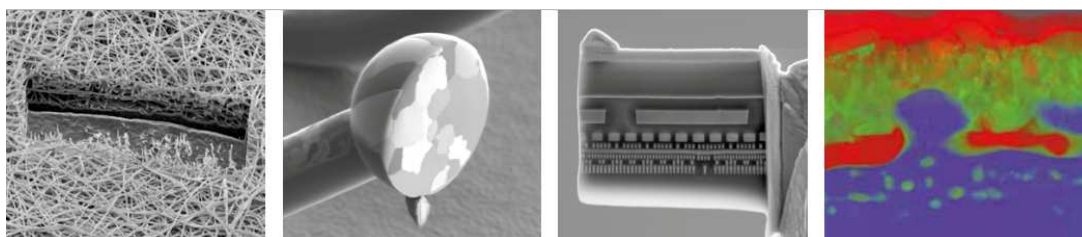


## Surface, Interface and Failure Analysis Service

Our equipments : ToF SIMS (GCIB), XPS, AFM, TEM STEM EDX EELS,  
SEM STEM EDX EBSD, FIB (Ga, Plasma Xe), ultra cryo-microtomy



### Areas of Expertise

▪ R&D ▪ INNOVATION ▪ QUALITY ▪ PRODUCTION ▪ FAILURE ANALYSIS

#### Materials

- Biological samples
- Ceramics
- Composites
- Glasses
- Metals, alloys
- Nanomaterials
- Polymers, textiles
- Semi-conductors

#### Industries

- Aerospace and defense
- Materials and Chemistry
- Building, Energy
- Consumer products (Automotive, Cosmetics, Packaging, Textile, Luxury goods, ...)
- Healthcare, Biotechnologies, Biology
- High Technology, micro-electronics

#### Thematics

- Adhesion / Assemblies / Interfaces
- Biocompatibility
- Contamination, Surface cleanliness, Additives migration
- Corrosion, Ageing, Durability
- Nanomaterials, REACH
- Surface structure and Chemistry
- Surface treatments or coatings, Multilayers
- Drug or active principle imaging

**Responsiveness / Confidentiality / Traceability**

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<http://www.tescan-analytics.com>